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# **Pin Configurations**

Figure 1. 28-pin TSOP pinout (Top View)

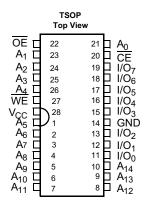
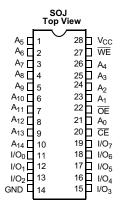


Figure 2. 28-pin SOJ pinout (Top View)



## **Selection Guide**

Description	Condition	-12	-15
Maximum access time (ns)		12	15
Maximum operating current (mA)		55	50
Maximum CMOS standby current (μA)	Commercial	500	-
	Commercial (L)	50	-
	Industrial	500	500
	Automotive-A	_	500



# **Maximum Ratings**

Output current into outputs (LOW)20 mA
Static discharge voltage (per MIL-STD-883, Method 3015)>2001 V
Latch-up current>200 mA

## **Operating Range**

Range	V <sub>CC</sub>	
Commercial	0 °C to +70 °C	$3.3~\text{V} \pm 300~\text{mV}$
Industrial	–40 °C to +85 °C	
Automotive-A	–40 °C to +85 °C	

### **Electrical Characteristics**

Over the Operating Range

Parameter [1]	Description	Test Con	ditiono		-12		-15	Unit
Parameter 17	Description	lest con	uitions	Min	Max	Min	Max	Oilit
V <sub>OH</sub>	Output HIGH voltage	Min $V_{CC}$ , $I_{OH} = -2$ .	0 mA	2.4	_	2.4	-	V
V <sub>OL</sub>	Output LOW voltage	Min $V_{CC}$ , $I_{OL} = 4.0$ n	nA	_	0.4	_	0.4	V
V <sub>IH</sub>	Input HIGH voltage			2.2	V <sub>CC</sub> + 0.3	2.2	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub> <sup>[1]</sup>	Input LOW voltage			-0.3	0.8	-0.3	0.8	V
I <sub>IX</sub>	Input leakage current			-1	+1	-1	+1	μΑ
I <sub>OZ</sub>	Output leakage current	$GND \le V_{IN} \le V_{CC}, C$	output disabled	<b>-</b> 5	+5	<b>-</b> 5	+5	μΑ
I <sub>CC</sub>	V <sub>CC</sub> operating supply current	$Max V_{CC}, I_{OUT} = 0 mA,$ $f = f_{MAX} = 1/t_{RC}$			55	_	50	mA
I <sub>SB1</sub>	Automatic CE power-down	$Max \ V_{CC}, \overline{CE} \ge V_{IH},$	Commercial	_	5	_	-	mA
	current – TTL inputs	$V_{IN} \ge V_{IH}$ , or $V_{IN} \le V_{IL}$ , $f = f_{MAX}$	Commercial (L)	_	4	_	-	mA
			Industrial	_	5	_	5	mA
			Automotive-A	_	-	_	5	mA
I <sub>SB2</sub>	Automatic CE Power-down	Max V <sub>CC</sub> ,	Commercial	_	500	_	-	μΑ
	current – CMOS inputs [2]	$\overline{CE} \ge V_{CC} - 0.3 \text{ V},$ $V_{IN} \ge V_{CC} - 0.3 \text{ V}, \text{ or}$	Commercial (L)	-	50	_	_	μА
		$V_{IN} \leq 0.3 V$	Industrial	_	500	_	500	μА
		$\overrightarrow{WE} \ge V_{CC} - 0.3 \text{ V or}$ $\overrightarrow{WE} \le 0.3 \text{ V,}$ $f = f_{MAX}$	Automotive-A	-	-	_	500	μА

#### Notes

- Minimum voltage is equal to -2.0 V for pulse durations of less than 20 ns.
- 2. Device draws low standby current regardless of switching on the addresses.

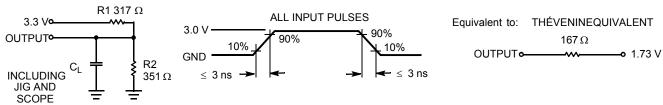


# Capacitance

Parameter [3]	Description	Test Conditions	Max	Unit
C <sub>IN</sub> : Addresses	Input capacitance	$T_A = 25 ^{\circ}\text{C}, f = 1 \text{MHz}, V_{CC} = 3.3 \text{V}$	5	pF
C <sub>IN</sub> : Controls			6	pF
C <sub>OUT</sub>	Output capacitance		6	pF

### **AC Test Loads and Waveforms**

Figure 3. AC Test Loads and Waveforms [4]



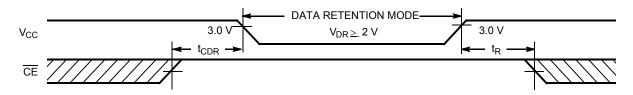
### **Data Retention Characteristics**

(Over the Operating Range - L version only)

Parameter	Description	Conditions	Min	Max	Unit
$V_{DR}$	V <sub>CC</sub> for data retention		2.0	_	V
I <sub>CCDR</sub>	Data retention current	$V_{CC} = V_{DR} = 2.0 \text{ V},$	0	20	μΑ
t <sub>CDR</sub>	Chip deselect to data retention time	$\overrightarrow{CE} \ge V_{CC} - 0.3 \text{ V},$ $V_{IN} \ge V_{CC} - 0.3 \text{ V or } V_{IN} \le 0.3 \text{ V}$	0	-	ns
t <sub>R</sub>	Operation recovery time		t <sub>RC</sub>	_	ns

### **Data Retention Waveform**

Figure 4. Data Retention Waveform



#### Notes

- Tested initially and after any design or process changes that may affect these parameters.
- Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I<sub>OL</sub>/I<sub>OH</sub> and capacitance C<sub>L</sub> = 30 pF.



# **Switching Characteristics**

Over the Operating Range

<b>5</b>	B	-	12		15				
Parameter [5]	Description	Min	Min Max		Max	Unit			
Read Cycle	Read Cycle								
t <sub>RC</sub>	Read cycle time	12	_	15	_	ns			
t <sub>AA</sub>	Address to data valid	_	12	_	15	ns			
t <sub>OHA</sub>	Data hold from address change	3	-	3	_	ns			
t <sub>ACE</sub>	CE LOW to data valid	_	12	_	15	ns			
t <sub>DOE</sub>	OE LOW to data valid	_	5	_	6	ns			
t <sub>LZOE</sub>	OE LOW to low Z [6]	0	_	0	_	ns			
t <sub>HZOE</sub>	OE HIGH to high Z [6, 7]	_	5	_	6	ns			
t <sub>LZCE</sub>	CE LOW to low Z [6]	3	_	3	_	ns			
t <sub>HZCE</sub>	CE HIGH to high Z [6, 7]	_	6	_	7	ns			
t <sub>PU</sub>	CE LOW to power-up	0	_	0	_	ns			
t <sub>PD</sub>	CE HIGH to power-down	_	12	_	15	ns			
Write Cycle [8,	9]	•	1	•	•				
t <sub>WC</sub>	Write cycle time	12	_	15	_	ns			
t <sub>SCE</sub>	CE LOW to write end	8	_	10	_	ns			
t <sub>AW</sub>	Address setup to write end	8	_	10	_	ns			
t <sub>HA</sub>	Address hold from write end	0	_	0	_	ns			
t <sub>SA</sub>	Address setup to write start	0	_	0	_	ns			
t <sub>PWE</sub>	WE pulse width	8	_	10	_	ns			
t <sub>SD</sub>	Data setup to write end	7	_	8	_	ns			
t <sub>HD</sub>	Data hold from write end	0	_	0	_	ns			
t <sub>HZWE</sub>	WE low to high Z <sup>[8]</sup>	_	7	_	7	ns			
t <sub>LZWE</sub>	WE high to low Z <sup>[6]</sup>	3	_	3	_	ns			

#### Notes

<sup>Notes
5. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I<sub>OL</sub>/I<sub>OH</sub> and capacitance C<sub>L</sub> = 30 pF.
6. At any given temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, t<sub>HZOE</sub> is less than t<sub>LZOE</sub>, and t<sub>HZWE</sub> is less than t<sub>LZWE</sub> for any given device.
7. t<sub>HZOE</sub>, t<sub>HZCE</sub>, t<sub>HZWE</sub> are specified with C<sub>L</sub> = 5 pF as in AC Test Loads. Transition is measured ±500 mV from steady state voltage.
8. The internal write time of the memory is defined by the overlap of CE LOW and WE LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.
9. The minimum write cycle time for write cycle #3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.</sup> 



# **Switching Waveforms**

Figure 5. Read Cycle No. 1 [10, 11]

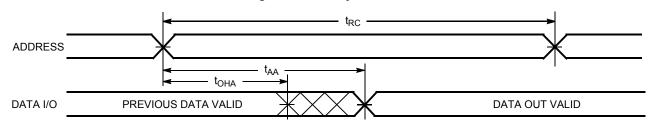
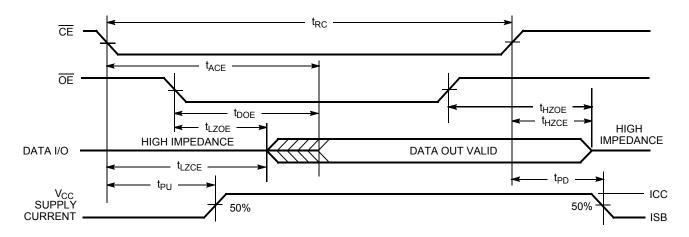


Figure 6. Read Cycle No. 2 [11, 12]



<sup>10. &</sup>lt;u>Dev</u>ice is continuously selected. <del>OE</del>, <del>CE</del> = V<sub>IL</sub>. 11. WE is HIGH for read cycle.

<sup>12.</sup> Address valid prior to or coincident with  $\overline{\sf CE}$  transition LOW.



# Switching Waveforms (continued)

Figure 7. Write Cycle No. 1 (WE Controlled) [13, 14, 15]

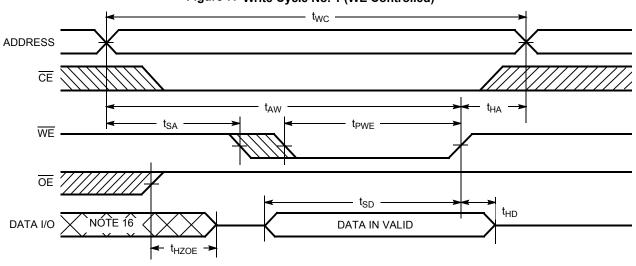
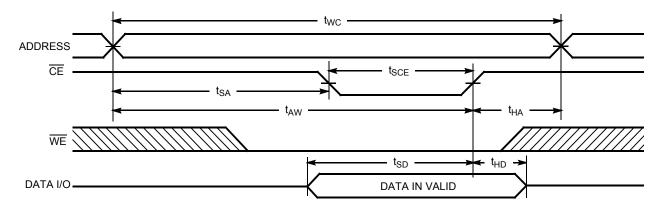


Figure 8. Write Cycle No. 2 (CE Controlled) [13, 14, 15]



<sup>13.</sup> The internal write time of the memory is defined by the overlap of  $\overline{\text{CE}}$  LOW and  $\overline{\text{WE}}$  LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.

14. Data I/O is high impedance if  $\overline{\text{OE}} = \text{V}_{\text{IE}}$ .

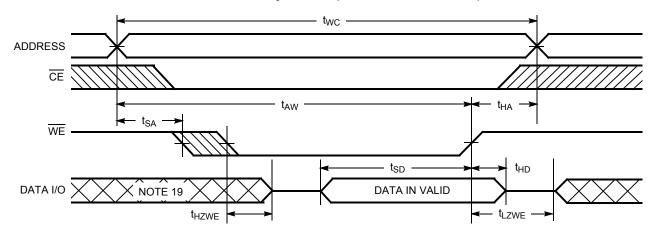
15. If  $\overline{\text{CE}}$  goes HIGH simultaneously with WE HIGH, the output remains in a high-impedance state.

16. During this period, the I/Os are in the output state and input signals should not be applied.



# Switching Waveforms (continued)

Figure 9. Write Cycle No. 3 ( $\overline{\text{WE}}$  Controlled,  $\overline{\text{OE}}$  LOW) [17, 18]



<sup>17.</sup> The minimum write cycle time for write cycle #3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.

18. If CE goes HIGH simultaneously with WE HIGH, the output remains in a high-impedance state.

19. During this period, the I/Os are in the output state and input signals should not be applied.



# **Truth Table**

CE	WE	OE	Input/Output	Mode	Power
Н	Х	Х	High Z	Deselect/Power-down	Standby (I <sub>SB</sub> )
L	Н	L	Data Out	Read	Active (I <sub>CC</sub> )
L	L	Х	Data In	Write	Active (I <sub>CC</sub> )
L	Н	Н	High Z	Deselect, Output disabled	Active (I <sub>CC</sub> )



# **Ordering Information**

Cypress offers other versions of this type of product in many different configurations and features. The following table contains only the list of parts that are currently available.

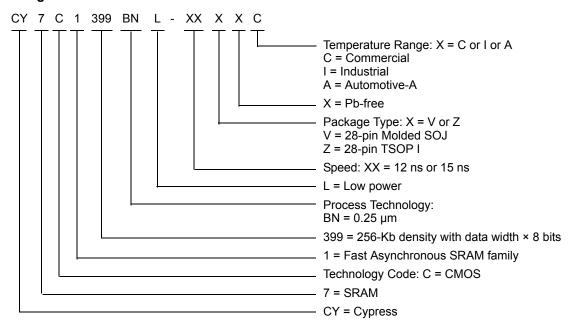
For a complete listing of all options, visit the Cypress website at www.cypress.com and refer to the product summary page at http://www.cypress.com/products or contact your local sales representative.

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Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
12	CY7C1399BN-12VXC	51-85031	28-pin molded SOJ (Pb-free)	Commercial
	CY7C1399BN-12ZXC	51-85071	28-pin TSOP I (Pb-free)	
	CY7C1399BNL-12ZXC		28-pin TSOP I (Pb-free)	
	CY7C1399BN-12VXI	51-85031	28-pin molded SOJ (Pb-free)	Industrial
15	CY7C1399BN-15ZXI	51-85071	28-pin TSOP I (Pb-free)	Industrial
	CY7C1399BN-15VXA	51-85031	28-pin molded SOJ (Pb-free)	Automotive-A

Contact your local sales representative regarding availability of these parts.

#### **Ordering Code Definitions**



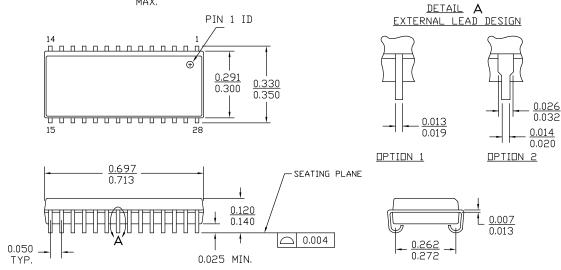


# **Package Diagrams**

#### Figure 10. 28-pin SOJ (300 Mils) V28.3 (Molded SOJ V21) Package Outline, 51-85031

#### NOTE :

- 1. JEDEC STD REF MO088
- 2. BODY LENGTH DIMENSION DOES NOT INCLUDE MOLD PROTRUSION/END FLASH MOLD PROTRUSION/END FLASH SHALL NOT EXCEED 0.006 in (0.152 mm) PER SIDE
- 3. DIMENSIONS IN INCHES  $\frac{\text{MIN.}}{\text{MAX.}}$

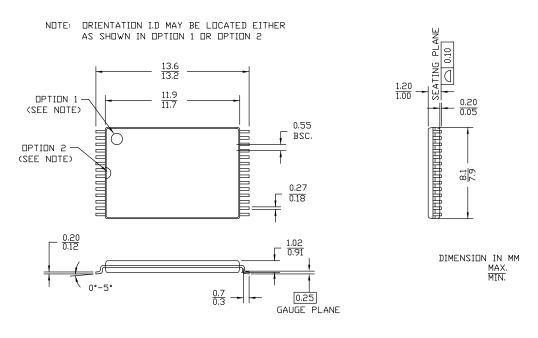


51-85031 \*E



# **Package Diagrams (continued)**

Figure 11. 28-pin TSOP I (8  $\times$  13.4  $\times$  1.2 mm) Z28 (Standard) Package Outline, 51-85071



51-85071 \*I



# **Acronyms**

Acronym	Description
CE	Chip Enable
CMOS	Complementary Metal Oxide Semiconductor
I/O	Input/Output
OE	Output Enable
SRAM	Static Random Access Memory
TSOP	Thin Small Outline Package
WE	Write Enable

# **Document Conventions**

## **Units of Measure**

Symbol	Unit of Measure			
°C	degree Celsius			
MHz	megahertz			
μΑ	microampere			
mA	milliampere			
mV	millivolt			
mW	milliwatt			
ns	nanosecond			
pF	picofarad			
V	volt			
W	watt			



# **Document History Page**

Document Title: CY7C1399BN, 256-Kbit (32 K × 8) Static RAM Document Number: 001-06490					
Revision	ECN	Orig. of Change	Submission Date	Description of Change	
**	423877	NXR	See ECN	New data sheet.	
*A	498575	NXR	See ECN	Added Automotive-A range Removed I <sub>OS</sub> parameter from DC Electrical Characteristics table Updated Ordering Information table.	
*B	2896382	AJU	03/19/2010	Removed obsolete part numbers from Ordering Information table and updated package diagrams.	
*C	3053362	PRAS	10/08/2010	Removed pruned part numbers CY7C1399BNL-15VXC and CY7C1399BNL-15VXCT. Added Ordering Code Definitions.	
*D	3383869	TAVA	09/26/2011	Added Commercial temperature range under Features section on page 1. Removed reference to AN1064-SRAM System Design Guidelines on page 1. Modified the notes in figures under Read cycle and Write cycle sections. Updated template according to current Cypress standards. Rearranged sections for better clarity. Revised package diagrams. Added Acronyms and Units of measure.	
*E	4121360	VINI	09/12/2013	Updated in new template.  Completing Sunset Review.	

Document Number: 001-06490 Rev. \*E Page 15 of 16



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